



HVCMOS Meeting 31.10.2024

DESY TB Results

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Overview

When: 30.09.-7.10.2024

Where: DESY test beam facility

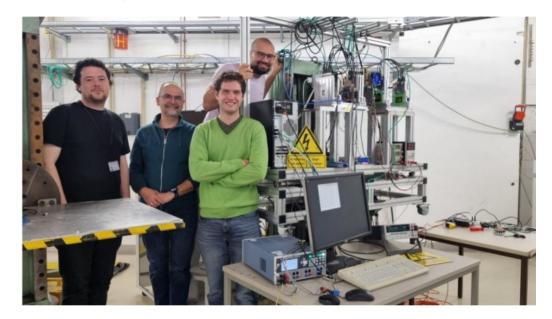
Measure Samples

- Non-Irradiated W8 (W8-0E0)
- W3-1E14
- W3-3E14
- W8-1E15
- W3-1E16

Beam

Particles: electrons

Energy: 4.2 GeV



Setup

Telescope: 6 Adenium planes

Telepix2 as ROI trigger Cooling setup (~ -15C°)





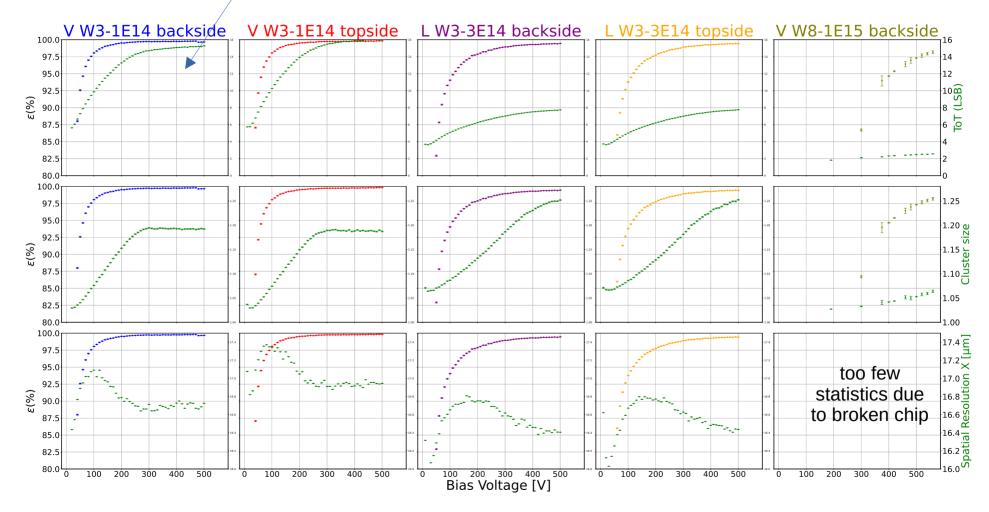
Settings Bias Voltage Scans

	W8-0E0 topside	W3-1E14 backside	W3-1E14 topside	W3-3E14 backside	W3-3E14 topside	W8-1E15 topside
Thr [V]	1	1.1	1.1	0.95	0.95	0.97
Range [V]	10-280	20-500	10-500	10-500	10-500	190-560



max ToT W8-0E0: 7.07 LSB (280V)







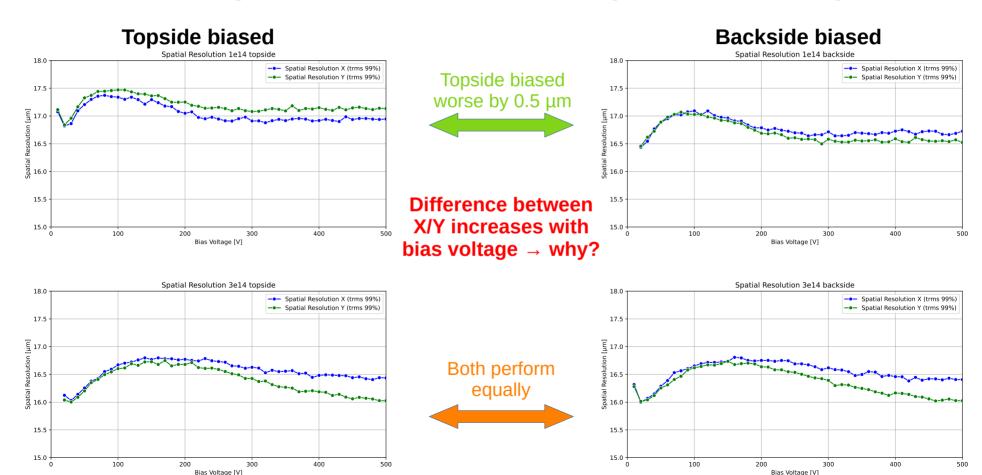
Results of high Bias Voltage Settings

Chip	Thr [V]	Bias Voltage [V]	ToT [LSB]	Cluster Size	Spatial Resolution [µm]
W8-0E0	1.0	280	7.07	1.16	17.12
W3-1E14 topside	1.1	500	15.99	1.19	16.95
W3-1E14 backside	1.1	500	15.28	1.19	16.73
W3-3E14 topside	0.95	500	7.81	1.25	16.44
W3-3E14 backside	0.95	500	7.79	1.25	16.41
W8-1E15	0.97	560	6.56	1.06	



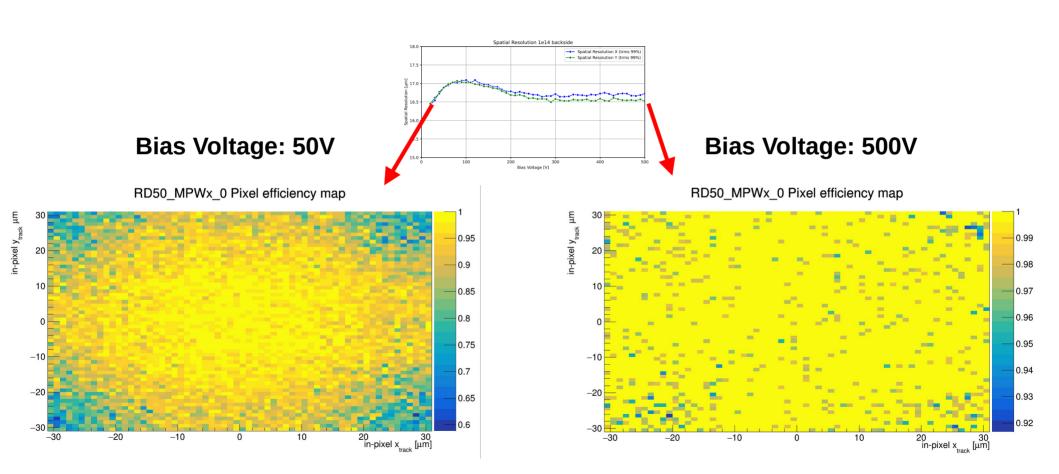


Spatial Resolution (X/Y vs HV)





In-Pixel Efficiency W3-1E14 backside

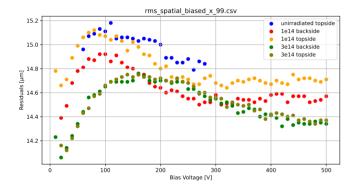


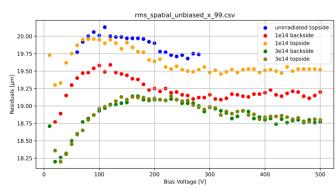




Residuals (X/Y vs HV)

Residuals X

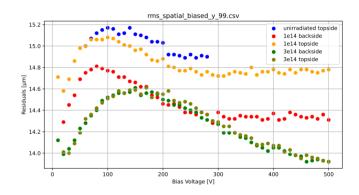


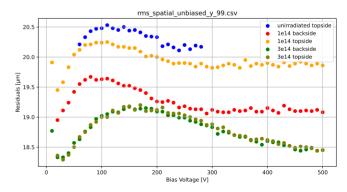


Biased truncated RMS (99%)



Residuals Y

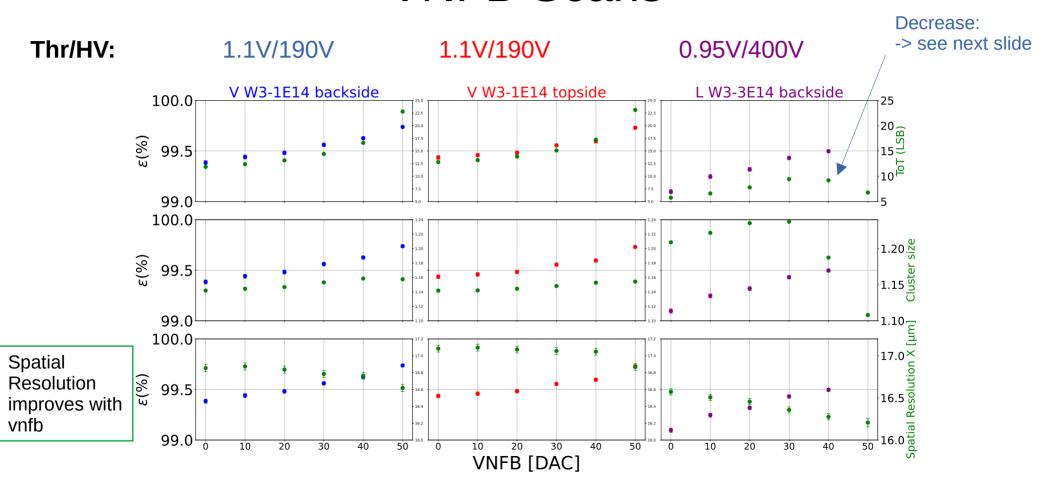








VNFB Scans



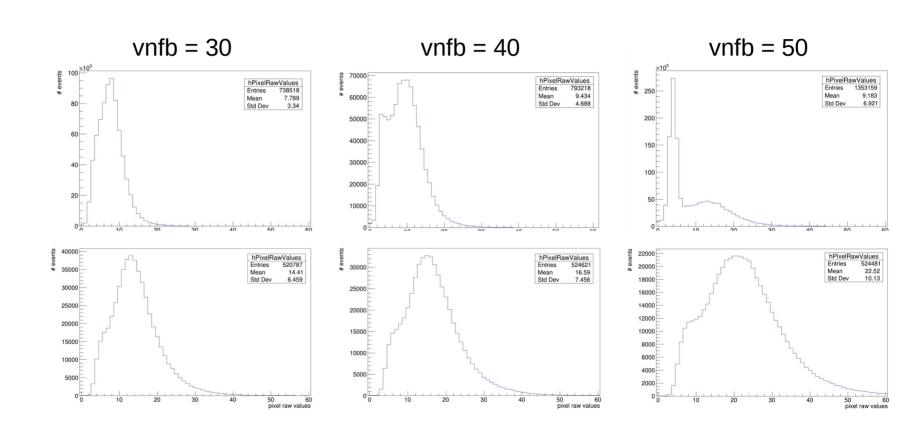




ToT comparison

W3-3E14 backside

W3-1E14 backside







Vnfb Direct Comparison

W3-1E14 backside	Vnfb = 20	Vnfb = 50	W3-3E14 backside	Vnfb = 20	Vnfb = 40
ToT [LSB]	13.14	22.80	ToT [LSB]	7.79	9.19
Cluster Size	1.15	1.16	Cluster Size	1.24	1.19
Spatial Resolution [µm]	16.84	16.62	Spatial Resolution [µm]	16.46	16.28
Efficiency [%]	99.48	99.74	Efficiency [%]	99.32	99.50





Summary

- HV Scan: Saturation of cluster size matches steady state of spatial resolution
- Spatial Resolution improves with higher vnfb (~0.2 μm)
- Efficiency improves slightly with vnfb (~0.2%)

Open Questions

- ToT of W3-1E14 is higher than ToT of W8-0E0 (15.27/7.07 LSB)
- Cluster Size of W3-3E14 (1.25) > W3-1E14 (1.19) > W8-0E0 (1.16)
- Difference between X/Y resolution increases with bias voltage